

APR 15 2004

In place of  
PTO-1449  
Form**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

U. S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

Complete if Known

SHEET	1	OF	1
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Application Number	10/712,460
Filing Date	November 13, 2003
Applicant(s)	Chia-Lin Chen, et al.
Art Unit	<del>4746</del> 2826
Examiner Name	To Be Determined C. Everhart
Attorney Docket Number	24061.42 (TSMC2002-1015)

**U. S. PATENT DOCUMENTS**

Examiner's Initials	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
CME	AA	2002/0009900	01/24/02	Tay et al.
	AB	5,371,396	12/06/94	Vinal et al.
	AC	5,521,127	05/28/96	Hori et al.
	AD	5,710,450	01/20/98	Chau et al.
	AE	5,840,125	11/24/98	Gronet et al.
	AF	5,943,230	08/24/99	Rinnen et al.
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	AH	6,020,260	02/01/00	Gardner
	AI	6,099,647	08/08/00	Yich et al.
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	AQ	6,399,445	06/04/02	Hattangady, et al.
	AR	6,402,850	06/11/02	Beinglass et al.
	AS	6,410,090	06/25/02	Wang
	AT	6,413,871	07/02/02	M'Saad et al.
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	AW	6,488,776	12/03/02	Wang
	AX	6,518,203	02/11/03	Narwankar et al.

**FOREIGN PATENT DOCUMENTS**

Examiner's Initials	Cite No.	Foreign Patent Document (Country Code - Number - Kind)	Publication Date MM-DD-YYYY	Patentee or Applicant of Cited Document	Translation Y/N

**OTHER PRIOR ART**

Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume, issue number(s), publisher, city/country where published
CME	AY	ARNUAD, F., ET AL., "Gate Oxide Process Impact on RNCE for Advanced CMOS Transistors", September 2002, ESSDERC '02, Firenze Italy, 21 pages.
CME	AZ	LI, GENE, "Total Solutions for Front-End Thermal Processing", Foresight, May 2001, Pages 41-45.
CME	BA	ZONCA, R., ET AL., "Ultra Thin NO/N <sub>2</sub> O Oxynitride Dielectric for Advanced Flash Memory Application: Single Wafer and Batch Technology", 6 pages.
CME	BB	"Gate Stack", World Wide Web <a href="http://www.appliedmaterials.com/products/gate_stack.html">http://www.appliedmaterials.com/products/gate_stack.html</a> , printed on February 17, 2003, 1 page.
CME	BC	"Technology Challenges for 100nm and Beyond Transistor and Capacitor Fabrication: Fig. 8", World Wide Web <a href="http://www.future-fab.com/assets/images/FFI11E1104F8.htm">http://www.future-fab.com/assets/images/FFI11E1104F8.htm</a> , printed on February 18, 2003, 1 page.

Examiner Signature	C. Everhart	Date Considered	10/15/04
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

In place of PTO-1449 Form		U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>				Application Number	10/712,460
				Filing Date	11/13/2003
				Applicant(s)	Chen et al.
				Art Unit	1748 2926
				Examiner Name	To Be Determined C. Everhart
				Attorney Docket Number	TSMC2002-1015/24061.42
SHEET	1	OF	1		

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FOREIGN PATENT DOCUMENTS					
Examiner's Initials	Cite No.	Foreign Patent Document (Country Code - Number - Kind)	Publication Date MM-DD-YYYY	Patentee or Applicant of Cited Document	Translation Y/N

NON-PATENT LITERATURE		
Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume-issue number(s), publisher, city/country where published
DATE	AC	Decoupled Plasma Nitridation (DPN), May 2001, Foresight, Pages 43-45.

Examiner Signature	<i>C. Juerkett</i>	Date Considered	10-15-04
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.